Notice of References Cited Application/Control No. 10/531,454 Examiner John Kreck Applicant(s)/Patent Under Reexamination DERIE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,132,355	10-2000	Derie, Rene	588/257
*	В	US-5,281,339	01-1994	Mainwaring et al.	210/705
*	С	US-5,860,908	01-1999	Forrester, Keith Edward	588/256
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	H	US-			
	1	US-			
	7	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05317894 A	12-1993	Japan	OGURA, YUJIRO	
	0					
	Р	,				
	Q			3		
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

	NOW ATEM BOOMENTO						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	x						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.